

Chipsmall Limited consists of a professional team with an average of over 10 year of expertise in the distribution of electronic components. Based in Hongkong, we have already established firm and mutual-benefit business relationships with customers from, Europe, America and south Asia, supplying obsolete and hard-to-find components to meet their specific needs.

With the principle of "Quality Parts, Customers Priority, Honest Operation, and Considerate Service", our business mainly focus on the distribution of electronic components. Line cards we deal with include Microchip, ALPS, ROHM, Xilinx, Pulse, ON, Everlight and Freescale. Main products comprise IC, Modules, Potentiometer, IC Socket, Relay, Connector. Our parts cover such applications as commercial, industrial, and automotives areas.

We are looking forward to setting up business relationship with you and hope to provide you with the best service and solution. Let us make a better world for our industry!



Contact us

Tel: +86-755-8981 8866 Fax: +86-755-8427 6832

Email & Skype: info@chipsmall.com Web: www.chipsmall.com

Address: A1208, Overseas Decoration Building, #122 Zhenhua RD., Futian, Shenzhen, China









STW70N60DM2

N-channel 600 V, 0.037 Ω typ., 66 A MDmesh™ DM2 Power MOSFET in a TO-247 package

Datasheet - production data

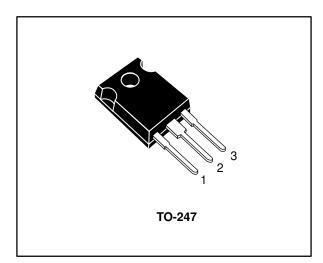
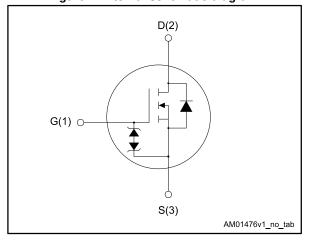


Figure 1: Internal schematic diagram



Features

Order code	V _{DS}	R _{DS(on)} max.	ΙD	Ртот
STW70N60DM2	600 V	0.042 Ω	66 A	446 W

- Fast-recovery body diode
- Extremely low gate charge and input capacitance
- Low on-resistance
- 100% avalanche tested
- Extremely high dv/dt ruggedness
- Zener-protected

Applications

Switching applications

Description

This high voltage N-channel Power MOSFET is part of the MDmesh $^{\text{TM}}$ DM2 fast recovery diode series. It offers very low recovery charge (Q_{rr}) and time (t_{rr}) combined with low $R_{DS(on)}$, rendering it suitable for the most demanding high efficiency converters and ideal for bridge topologies and ZVS phase-shift converters.

Table 1: Device summary

Order code	Marking	Package	Packing
STW70N60DM2	70N60DM2	TO-247	Tube

STW70N60DM2 Contents

Contents

1	Electric	cal ratings	3
2	Electric	cal characteristics	4
	2.1	Electrical characteristics (curves)	6
3	Test cir	œuits	8
4	Packag	e information	9
	_	TO-247 package information	
5	Revisio	on history	11

STW70N60DM2 Electrical ratings

1 Electrical ratings

Table 2: Absolute maximum ratings

Symbol	Parameter	Value	Unit
V _{GS}	Gate-source voltage	±25	V
1_	Drain current (continuous) at T _{case} = 25 °C		Α
ID	Drain current (continuous) at T _{case} = 100 °C	42	A
I _{DM} ⁽¹⁾	Drain current (pulsed)	264	Α
P _{TOT}	Total dissipation at T _{case} = 25 °C	446	W
dv/dt ⁽²⁾	Peak diode recovery voltage slope 50		V/ns
dv/dt ⁽³⁾	MOSFET dv/dt ruggedness 50		V/IIS
T _{stg}	Storage temperature -55 to 150		°C
Tj			10

Notes:

Table 3: Thermal data

Symbol	Parameter	Value	Unit
R _{thj-case}	Thermal resistance junction-case	0.28	0C/M
R _{thj-amb}	Thermal resistance junction-ambient	50	°C/W

Table 4: Avalanche characteristics

Symbol	Parameter	Value	Unit
lar	Avalanche current, repetitive or not repetitive (Pulse width limited by $T_{\text{jmax}})$	10	Α
Eas	Single pulse avalanche energy (starting $T_j = 25$ °C, $I_D = I_{AR}$, $V_{DD} = 50$ V)	1500	mJ

 $^{^{\}left(1\right)}$ Pulse width is limited by safe operating area.

 $^{^{(2)}}$ $I_{SD} \leq 66$ A, di/dt=900 A/ μ s; V_{DS} peak < $V_{(BR)DSS},~V_{DD}$ = 400 V.

 $^{^{(3)}}$ V_{DS} \leq 480 V.

2 Electrical characteristics

(T_{case} = 25 °C unless otherwise specified)

Table 5: Static

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$V_{(BR)DSS}$	Drain-source breakdown voltage	$V_{GS} = 0 \text{ V}, I_D = 1 \text{ mA}$	600			V
Zara gata valtaga drain		V _{GS} = 0 V, V _{DS} = 600 V			10	
I _{DSS} Zero gate voltage drain current	$V_{GS} = 0 \text{ V}, V_{DS} = 600 \text{ V},$ $T_{case} = 125 \text{ °C}$			100	μΑ	
lgss	Gate-body leakage current	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 25 \text{ V}$			±5	μΑ
$V_{\text{GS(th)}}$	Gate threshold voltage	$V_{DS} = V_{GS}$, $I_D = 250 \mu A$	3	4	5	V
R _{DS(on)}	Static drain-source on- resistance	V _{GS} = 10 V, I _D = 33 A		0.037	0.042	Ω

Table 6: Dynamic

Symbol	Parameter Test conditions		Min.	Тур.	Max.	Unit
C _{iss}	Input capacitance		-	5508	1	
Coss	Output capacitance	$V_{DS} = 100 \text{ V}, f = 1 \text{ MHz},$	-	241	ı	pF
Crss	Reverse transfer capacitance	$I_D = 0 A$	-	2.8	-	ρ.
Coss eq. (1)	Equivalent output capacitance	$V_{DS} = 0$ to 480 V, $V_{GS} = 0$ V	-	470	-	рF
R _G	Intrinsic gate resistance	f = 1 MHz, I _D = 0 A	-	2	-	Ω
Qg	Total gate charge	$V_{DD} = 480 \text{ V}, I_{D} = 66 \text{ A},$	-	121	-	
Q _{gs}	Gate-source charge	V _{GS} = 10 V (see Figure 15: "Test circuit for gate charge	-	26	-	nC
Q_{gd}	Gate-drain charge	behavior")	-	61	-	

Notes:

Table 7: Switching times

Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
$t_{d(on)}$	Turn-on delay time	$V_{DD} = 300 \text{ V}, I_D = 33 \text{ A}$	ı	32	ı	
tr	Rise time	$R_G = 4.7 \Omega$, $V_{GS} = 10 V$ (see Figure 14: "Test circuit for	-	67	-	20
t _{d(off)}	Turn-off delay time	resistive load switching times"	-	112	-	ns
t _f	Fall time	and)	-	10.4	-	

 $^{^{(1)}}$ C_{oss eq.} is defined as a constant equivalent capacitance giving the same charging time as C_{oss} when V_{DS} increases from 0 to 80% V_{DSS}.

Table 8: Source-drain diode

	Table of Course arani aloue					
Symbol	Parameter	Test conditions	Min.	Тур.	Max.	Unit
I _{SD}	Source-drain current		-		66	Α
I _{SDM} ⁽¹⁾	Source-drain current (pulsed)		1		264	Α
V _{SD} ⁽²⁾	Forward on voltage	V _{GS} = 0 V, I _{SD} = 66 A	-		1.6	V
t _{rr}	Reverse recovery time	$I_{SD} = 66 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	150		ns
Qrr	Reverse recovery charge	V _{DD} = 60 V (see Figure 16: "Test circuit for inductive	1	0.75		μC
I _{RRM}	Reverse recovery current	load switching and diode recovery times")	-	10.5		Α
t _{rr}	Reverse recovery time	$I_{SD} = 66 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s},$	-	250		ns
Qrr	Reverse recovery charge	$V_{DD} = 60 \text{ V}, T_j = 150 \text{ °C}$ (see Figure 16: "Test circuit	-	2.5		μC
I _{RRM}	Reverse recovery current	for inductive load switching and diode recovery times")	-	20.7		Α

Notes:

 $^{^{\}left(1\right) }$ Pulse width is limited by safe operating area.

 $^{^{(2)}}$ Pulse test: pulse duration = 300 $\mu s,$ duty cycle 1.5%.

2.1 Electrical characteristics (curves)

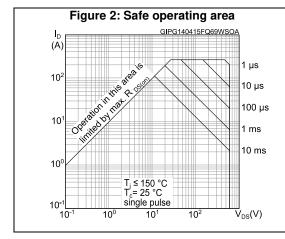


Figure 3: Thermal impedance

K

-0.2

0.01

0.02

Zth=k Rthj-c
d=tp/t

10⁻²

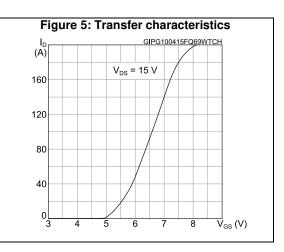
10⁻³

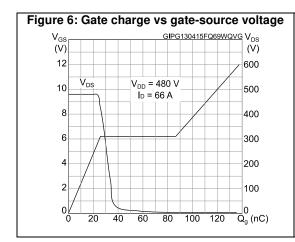
10⁻³

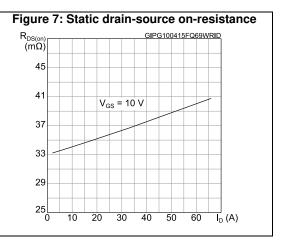
10⁻³

10⁻¹

tp(s)







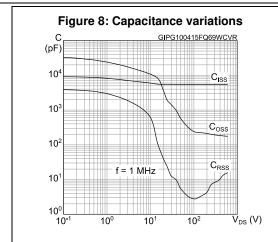


Figure 10: Normalized on-resistance vs temperature

R_{DS(on)} GIPG18052015RON

2.2

V_{GS}= 10 V

1.8

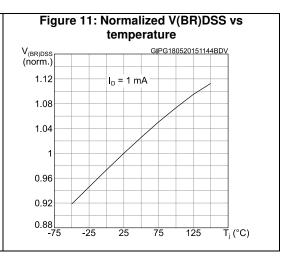
1.4

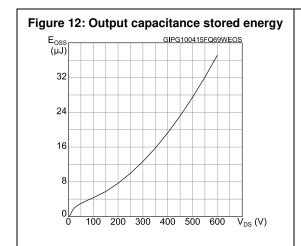
1.0

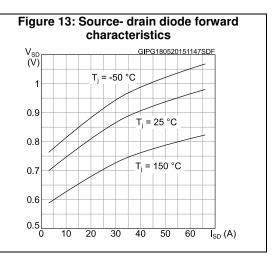
0.6

0.2

-75
-25
25
75
125
T_j(°C)





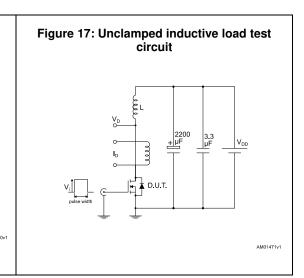


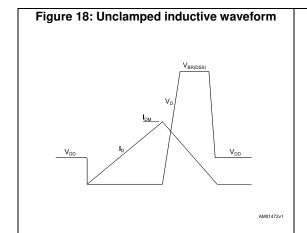
Test circuits STW70N60DM2

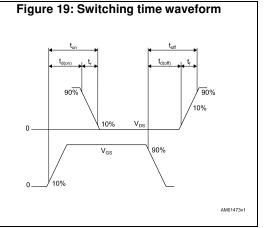
3 Test circuits

Figure 14: Test circuit for resistive load switching times

Figure 16: Test circuit for inductive load switching and diode recovery times







4 Package information

In order to meet environmental requirements, ST offers these devices in different grades of ECOPACK® packages, depending on their level of environmental compliance. ECOPACK® specifications, grade definitions and product status are available at: **www.st.com**. ECOPACK® is an ST trademark.

4.1 TO-247 package information

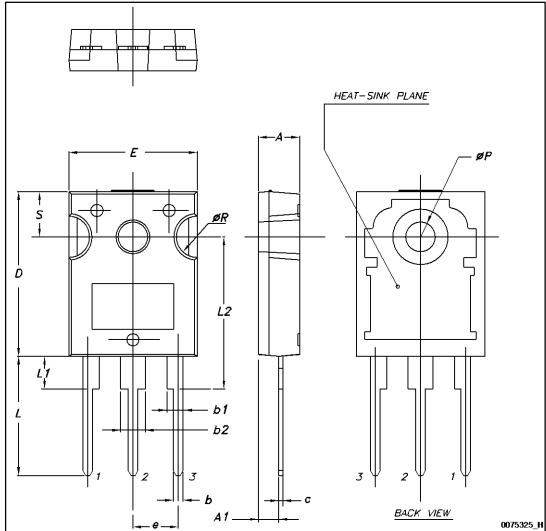


Figure 20: TO-247 package outline

Table 9: TO-247 package mechanical data

Dim		mm.	
Dim.	Min.	Тур.	Max.
Α	4.85		5.15
A1	2.20		2.60
b	1.0		1.40
b1	2.0		2.40
b2	3.0		3.40
С	0.40		0.80
D	19.85		20.15
Е	15.45		15.75
е	5.30	5.45	5.60
L	14.20		14.80
L1	3.70		4.30
L2		18.50	
ØP	3.55		3.65
ØR	4.50		5.50
S	5.30	5.50	5.70

STW70N60DM2 Revision history

5 Revision history

Table 10: Document revision history

Date	Revision	Changes
04-Sep-2014	1	First release.
18-May-2015	2	Document status promoted from preliminary to production data. Added Section 2.1 Electrical characteristics (curves).
08-Jul-2015	3	Text and formatting changes throughout document in Section Electrical characteristics: - updated Tables Dynamic and Source-drain diode
09-Dec-2015	4	Updated Table 4: "Avalanche characteristics".

IMPORTANT NOTICE - PLEASE READ CAREFULLY

STMicroelectronics NV and its subsidiaries ("ST") reserve the right to make changes, corrections, enhancements, modifications, and improvements to ST products and/or to this document at any time without notice. Purchasers should obtain the latest relevant information on ST products before placing orders. ST products are sold pursuant to ST's terms and conditions of sale in place at the time of order acknowledgement.

Purchasers are solely responsible for the choice, selection, and use of ST products and ST assumes no liability for application assistance or the design of Purchasers' products.

No license, express or implied, to any intellectual property right is granted by ST herein.

Resale of ST products with provisions different from the information set forth herein shall void any warranty granted by ST for such product.

ST and the ST logo are trademarks of ST. All other product or service names are the property of their respective owners.

Information in this document supersedes and replaces information previously supplied in any prior versions of this document.

© 2015 STMicroelectronics - All rights reserved

